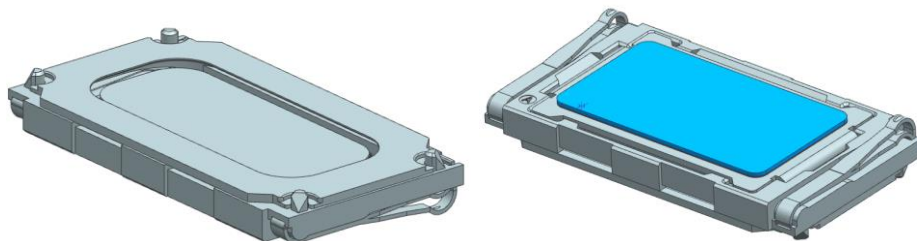


**RA8x15 Receiver
with pad at rear side**

BR815S15YN32P

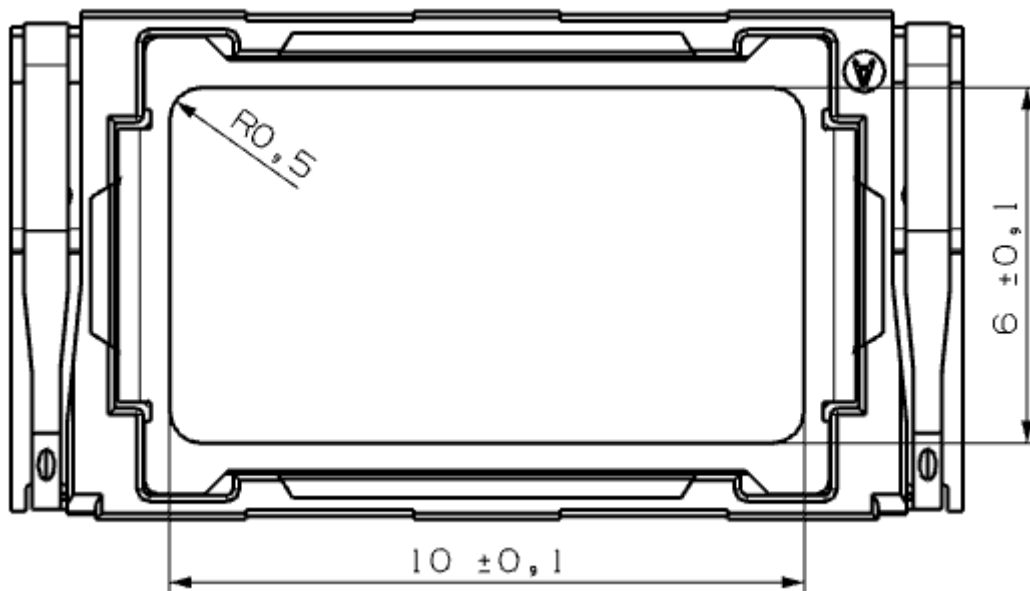
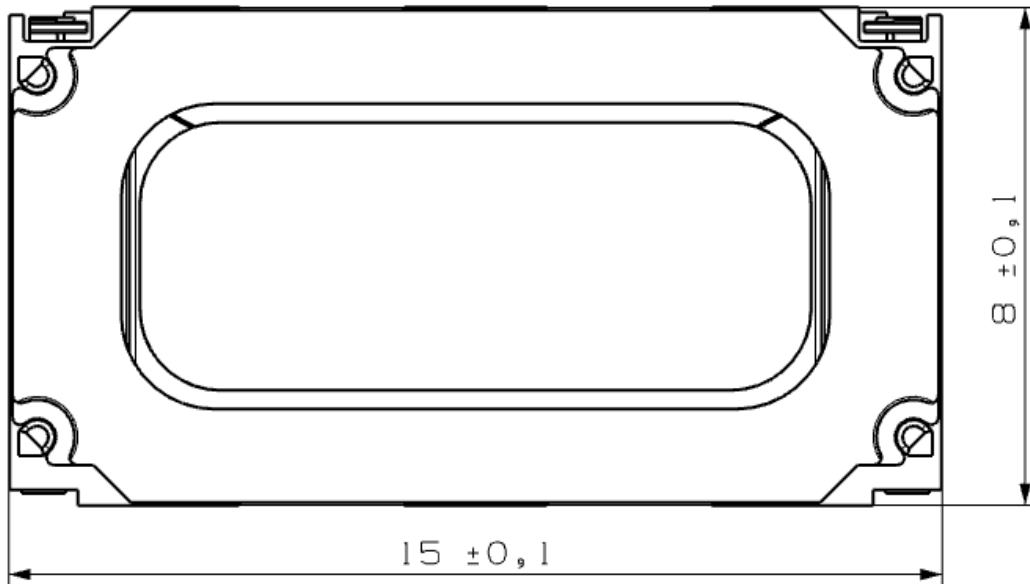


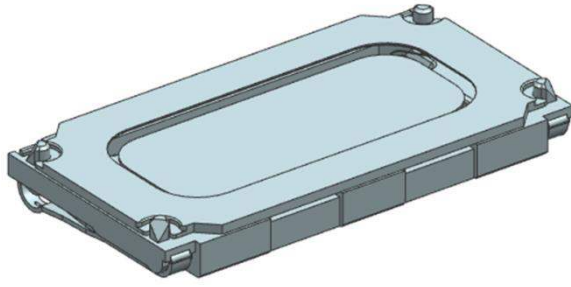
Revision

Date	Version	Status	Changes	Approver
2015/07/21	V0.1	Draft	First release	Shixin Qin
2015/08/03	V0.2	Draft	Environmental tests added	Shixin Qin

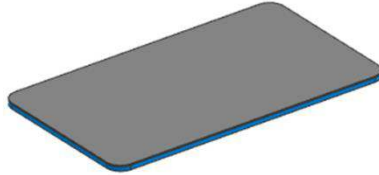
1. Mechanical Characteristics

1.1. Mechanical Dimensions





Nith 1.5mm



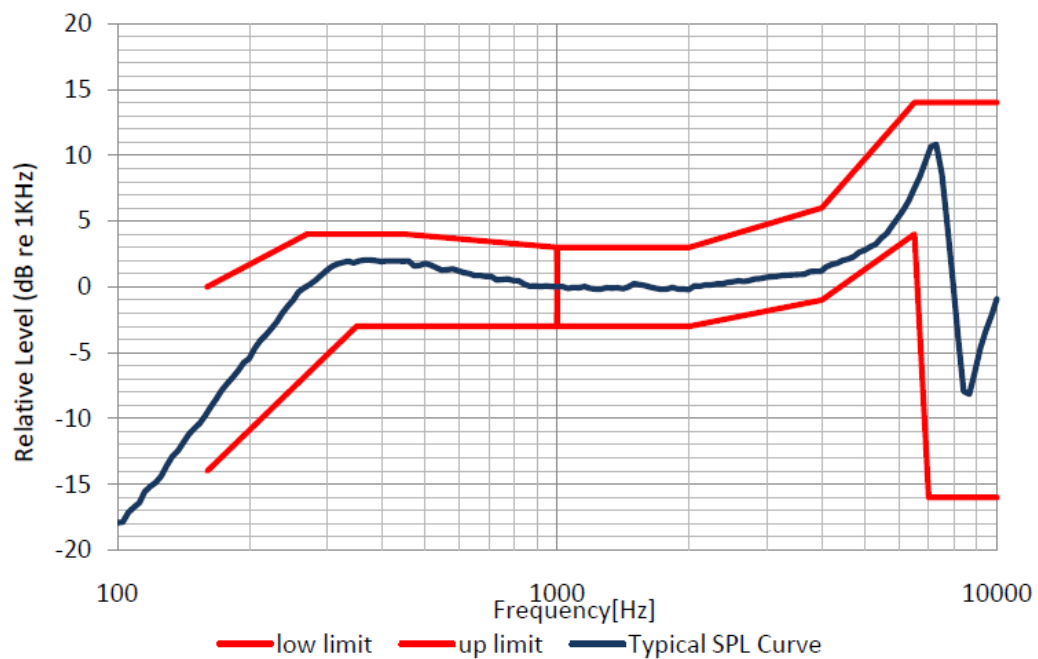
Pad 0.2mm

Missing information see specification Seltech Doc. BR815S15YN32

2. Electro-Acoustic Characteristics

2.1. Frequency response

Typical frequency response measured on baffle according to chapter 2.6
(D=1cm; P=10mW @32Ω)



2.2. Electro-Acoustic Parameters

Receiver mounted in baffle acc. to chapter 2.1

- | | |
|--|------------------|
| 1. Rated impedance | Z: 32Ω |
| 2. Voice coil resistance | R: 28.8Ω±2.88Ω |
| 3. Resonance frequency | f0: 300Hz±45Hz |
| 4. Maximum diaphragm excursion above the top of the surface: | 0.2mm |
| 5. Nominal characteristic sensitivity | 89 dBPa re 20uPa |
| (@baffle, 10mW, 1cm; average from 1KHz to 3KHz) | |

2.3. Power Handling

Receiver mounted in lifetime test device (open rear/open front).

- | | |
|----------------------|------------|
| 1. RATED NOISE POWER | 10mW (RMS) |
|----------------------|------------|

(500h, pink noise with the weighting, crest factor is 12dB)

Type	Order	F0[Hz]
High Pass	1	250
High Pass	10	100
Low Pass	10	3500

- | | |
|-------------------|------------|
| 2. OVERLOAD POWER | 30mW (RMS) |
|-------------------|------------|

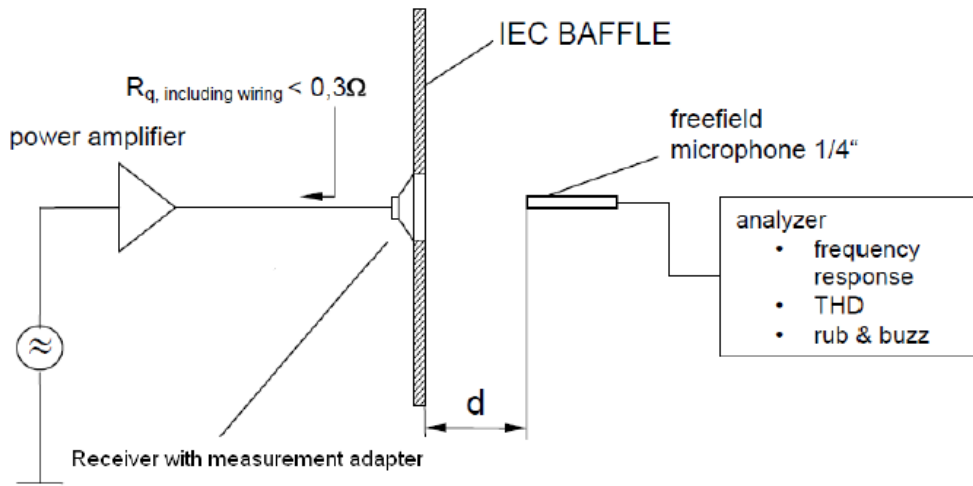
(50h, sinusoidal, 200Hz~6 KHz, allow increase R&B)

- | | |
|---------------------------|------------|
| 3. RATED SINUSOIDAL POWER | 10mW (RMS) |
|---------------------------|------------|

(50h, sinusoidal, 200Hz~6 KHz, no damage)

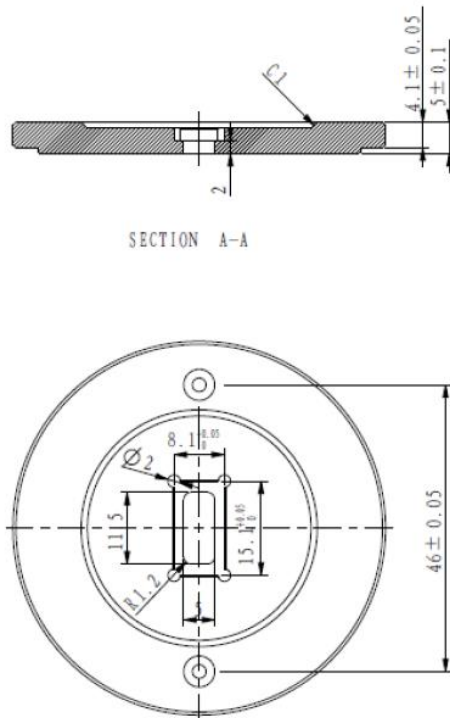
2.4. Measurement setup on baffle

2.4.1. Measured setup



D=1.0cm.

2.4.2. Measure adapter



3. Environmental tests

3.1. Qualification Tests

According to our milestone plan (Product Creation Process), a complete qualification test will be done at design validation on products, manufactured under serial conditions and 1x per year and product family. The qualification process covers all tests described under 3.5 and a complete inspection takes place.

3.2. Requalification Tests

1x per month and product family samples are taken and submitted to tests described under 3.5.2

3.3. Samples Size, Sequence

Unless otherwise stated 20 arbitrary new samples will be used to perform each test for both, qualification and requalification test as described under 3.1 and 3.2.

3.4. Period of Shelf-Life

The period of shelf-life is 5 years

3.5. Testing Procedures

3.5.1.Storage Tests

3.5.2.Operating Tests

3.5.3.Salt Mist Test

3.5.4.Shock Resistance Test (Free Fall Test) – protected product

3.5.5.Impact Durability Test (Tumble Test) – protected product

3.5.6.G-Force Test

3.5.7.Resistance to Electronic Discharge

3.5.8.Sine Vibration Test

3.5.9.Random Vibration Test

3.5.10. Mechanical Shock